

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|-------|---|---|------------------|---------|------------------|
| | | "5876902".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| L1 | 1376 | burn-in near testing | USPAT | OR | OFF | 2005/01/21 19:35 |
| L2 | 760 | burn-in near testing and wafer | USPAT | OR | OFF | 2005/01/21 20:33 |
| L3 | 1 | "5594273".pn. and burn-in near test\$3 | USPAT | OR | OFF | 2005/01/21 21:06 |
| L4 | 1 | "6472239".pn. | USPAT | OR | OFF | 2005/01/21 21:07 |
| L5 | 2128 | 438/128 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/01/21 21:08 |
| L6 | 1007 | 438/129 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/01/21 21:21 |
| L7 | 297 | 438/130 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/01/21 21:33 |
| L8 | 372 | 438/131 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/01/21 21:40 |
| L9 | 511 | 438/132 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/01/21 21:40 |
| S1 | 21743 | (bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) with (semiconductor or die or chip or dice or IC) | USPAT | OR | ON | 2004/08/08 20:31 |
| S2 | 21662 | (bad or defect\$3 or "non functional") with (semiconductor or die or chip or dice or IC) | USPAT | OR | ON | 2004/08/08 20:31 |

| | | | | | | |
|-----|------|---|-------|----|-----|------------------|
| S3 | 5340 | (bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) | USPAT | OR | ON | 2004/08/08 20:32 |
| S4 | 5336 | (bad or defect\$3 or "non functional" or (none or "not" or non) adj function\$2) near (semiconductor or die or chip or dice or IC) | USPAT | OR | ON | 2004/08/08 20:32 |
| S5 | 2980 | (bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and wafer | USPAT | OR | ON | 2004/08/08 20:38 |
| S6 | 1326 | ((bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and wafer) and (repair\$3 or reconfigur\$3 or isolat\$3) | USPAT | OR | ON | 2004/08/08 20:34 |
| S7 | 206 | (bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) with (repair\$3 or reconfigur\$3 or isolat\$3) and wafer | USPAT | OR | ON | 2004/08/08 20:57 |
| S8 | 1 | "5255051".PN. | USPAT | OR | OFF | 2004/08/08 20:55 |
| S9 | 1 | "5327338".PN. | USPAT | OR | OFF | 2004/08/08 20:55 |
| S10 | 1 | "5386221".PN. | USPAT | OR | OFF | 2004/08/08 20:55 |
| S11 | 1 | "5786632".PN. | USPAT | OR | OFF | 2004/08/08 20:55 |
| S12 | 1 | "5876902".PN. | USPAT | OR | OFF | 2004/08/08 20:55 |
| S13 | 1 | "5895581".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S14 | 1 | "5255051".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S15 | 1 | "5255051".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S16 | 1 | "5327338".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S17 | 1 | "5386221".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S18 | 1 | "5786632".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S19 | 1 | "6262390".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S20 | 1 | "6115175".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S21 | 1 | "6088379".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S22 | 1 | "6048753".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S23 | 1 | "6037967".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S24 | 1 | "5990566".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |

| | | | | | | |
|-----|----|--|-------|----|-----|------------------|
| S25 | 1 | "5895581".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S26 | 1 | "5876902".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S27 | 1 | "5786632".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S28 | 1 | "5386221".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S29 | 1 | "5327338".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S30 | 1 | "5255051".PN. | USPAT | OR | OFF | 2004/08/08 20:56 |
| S31 | 1 | "6262390".PN. | USPAT | OR | OFF | 2004/08/08 20:58 |
| S32 | 1 | "6115175".PN. | USPAT | OR | OFF | 2004/08/08 20:58 |
| S33 | 1 | "6088379".PN. | USPAT | OR | OFF | 2004/08/08 20:58 |
| S34 | 1 | "6048753".PN. | USPAT | OR | OFF | 2004/08/08 20:58 |
| S35 | 1 | "6037967".PN. | USPAT | OR | OFF | 2004/08/08 20:58 |
| S36 | 1 | "5990566".PN. | USPAT | OR | OFF | 2004/08/08 20:59 |
| S37 | 1 | "5895581".PN. | USPAT | OR | OFF | 2004/08/08 20:59 |
| S38 | 1 | "5876902".PN. | USPAT | OR | OFF | 2004/08/08 20:59 |
| S39 | 1 | "5786632".PN. | USPAT | OR | OFF | 2004/08/08 21:00 |
| S40 | 1 | "5386221".PN. | USPAT | OR | OFF | 2004/08/08 21:00 |
| S41 | 1 | "5327338".PN. | USPAT | OR | OFF | 2004/08/08 21:00 |
| S42 | 1 | "5255051".PN. | USPAT | OR | OFF | 2004/08/08 21:01 |
| S43 | 13 | (bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) with electrically near (isolat\$3) | USPAT | OR | OFF | 2004/08/09 00:44 |
| S44 | 16 | (bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) with electric\$4 near (isolat\$3) | USPAT | OR | OFF | 2004/08/09 00:43 |
| S45 | 0 | ((bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) with electric\$4 near (isolat\$3)) and burn near in near test | USPAT | OR | OFF | 2004/08/09 00:43 |
| S46 | 28 | (bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and burn near in near test | USPAT | OR | OFF | 2004/08/09 00:44 |

| | | | | | | |
|-----|------|--|---|----|-----|------------------|
| S47 | 30 | (bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and burn near in near test\$3 | USPAT | OR | OFF | 2004/08/09 00:44 |
| S48 | 47 | (bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and burn near in near test\$3 | USPAT | OR | ON | 2004/08/09 00:48 |
| S49 | 12 | ((bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and burn near in near test\$3) and electric\$4 with isolat\$3 | USPAT | OR | ON | 2004/08/09 01:34 |
| S50 | 0 | (bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) same burn near in near test\$3 | USPAT | OR | ON | 2004/08/09 01:33 |
| S51 | 9 | "5829128" and "6032356" | USPAT | OR | ON | 2004/08/09 01:25 |
| S52 | 65 | "5829128" or "6032356" | USPAT | OR | ON | 2004/08/09 01:25 |
| S53 | 179 | (bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) same (burn near in or "burn-in") near test\$3 | USPAT | OR | ON | 2004/08/09 01:34 |
| S54 | 17 | ((bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) same (burn near in or "burn-in") near test\$3) and electric\$4 with isolat\$3 | USPAT | OR | ON | 2004/08/09 03:40 |
| S55 | 2 | "6600171".pn. or "6680213".pn. | USPAT | OR | ON | 2004/08/09 03:47 |
| S56 | 1972 | 257/750 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/09 03:50 |
| S57 | 2657 | 257/690 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/09 03:56 |

| | | | | | | |
|-----|------|---|---|----|-----|------------------|
| S58 | 1973 | 257/691 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/09 04:08 |
| S59 | 2650 | 257/700 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/09 04:22 |
| S60 | 4668 | 257/758 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/09 05:30 |
| S61 | 2 | "5543364".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/09 05:25 |
| S62 | 923 | 257/759 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/09 05:43 |
| S63 | 1671 | 257/779 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/09 05:44 |
| S64 | 5 | "6214630" | USPAT | OR | OFF | 2005/01/21 12:20 |
| S65 | 1 | "6214630" and redistribution | USPAT | OR | OFF | 2005/01/21 12:21 |
| S66 | 1 | "6214630" and redistribution and defective and repair | USPAT | OR | OFF | 2005/01/21 12:22 |
| S67 | 3 | 438/128-132.ccls. and defect\$3 and redistribution and repair | USPAT | OR | OFF | 2005/01/21 19:35 |